

**Notice of References Cited**

Application/Control No.

10/749,143

Applicant(s)/Patent Under  
Reexamination  
JACKSON ET AL.

Examiner

S. Devi, Ph.D.

Art Unit

1645

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 00/12535	03-2000	PCT	Jackson et al.	
	O					
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	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Allunans et al. APMIS 106: 1181-1187, December 1998
	V	Schlecht et al. Naturwissenschaften 80: 9-17, 1993
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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